MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PLED

AOD403

Product specification





General Features

- -30 V,-70A, RDS(ON) =5.5mΩ@VGS = 10V
- Fast switching
- Green Device Available

Application

- MB / VGA / Vcore
- POL Applications
- Load Switch
- LED Applicatio

Reference News

PACKAGE OUTLINE	Pin Configuration	Marking
	o G	MSKSEMI AOD403
TO-252	ŝ	



Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
	Drain-Source Voltage		
VDS	Drain Godres Voltage	-30	V
VGS	Gate-Source Voltage	±20	V
ID	Drain Current – Continuous (T _C =25C)	-70	А
	Drain Current – Continuous (TC=100C)	-44	А
IDM	Drain Current – Pulsed ¹	-280	А
PD	Power Dissipation (TC=25C)	73.5	W
	Power Dissipation – Derate above 25C	0.58	W/ C
TSTG	Storage Temperature Range	-55 to 150	С
TJ	Operating Junction Temperature Range	-55 to 150	С

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient	· 	62	C/ W
Reuc	Thermal Resistance Junction to Case		1.7	C/ W

Electrical Characteristics (TJ=25 ℃, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} =0V , I_D =-250uA	-30			V
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 250 , I _D =-1mA		-0.03		V/ C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-30V , V _{GS} =0V , T _J =250			- 1	uA
.033		V _{DS} =-24V , V _{GS} =0V , T _J =1250			-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA



On Characteristics

		V _{GS} =-10V , I _D =-10A		5.5	8.0	mΩ
R _{DS(ON)}	Static Drain-Source On-Resistance	V_{GS} =-4.5V , I_D =-8A				0
				7.5	10	mΩ
V _{GS(th)}	Gate Threshold Voltage		-1.0	-1.6	-2.5	V
	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =-250uA				
$\triangle V_{GS(th)}$				4		mV/ C
gfs	Forward Transconductance	V _{DS} =-10V , I _D =-10A		14		S

Dynamic and switching Characteristics

Dynamic	and Switching	Characteristics			
Qg	Total Gate Charge ^{2,3}			35	
Qgs	Gate-Source Charge ^{2, 3}	V _{DS} =-15V , V _{GS} =-4.5V , I _D =-10A		10.8	 nC
Q _{qd}	Gate-Drain Charge ^{2,3}		· 	10.6	
T _{d(on)}	Turn-On Delay Time ^{2,3}			24.5	
Tr	Rise Time ^{2,3}	V_{DD} =-15 V , V_{GS} =-10 V , R_{G} =6 Ω		10.5	 ns
$T_{d(off)}$	Turn-Off Delay Time ^{2, 3}	I _D =-1A	· 	156.8	
Tf	Fall Time ^{2,3}			50	
C _{iss}	Input Capacitance			3300	
Coss	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , F=1MHz		410	 pF
C _{rss}	Reverse Transfer Capacitan	ce		280	
Rg	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz		8.5	 Ω

Drain- Source Diode Characteristics and Maximum Ratings

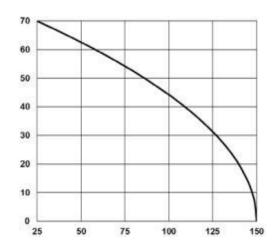
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V , Force Current			-70	Α
I _{SM}	Pulsed Source Current	vg-vb-ov , r orce current			-140	Α
V _{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , T _J =250			- 1.2	V

Note:

- 1 . Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width $~\leq~300\,\text{us}$, duty cycle $~\leq~2\%$.
- 3. Essentially independent of operating temperature.



-ID , Continuous Drain Current



TJ ,JunctionTemperature(°C)

Fig. 1 Continuous Drain Current vs. TC

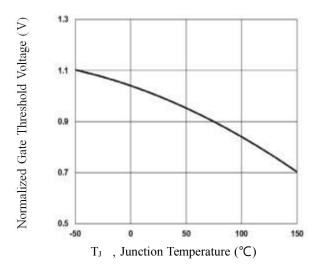
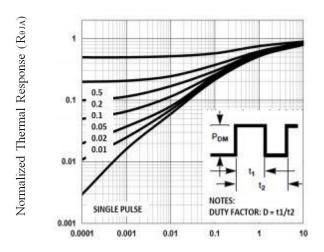


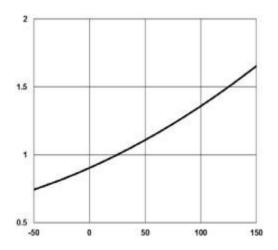
Fig. 3 Normalized Vth vs. TJ



Square Wave Pulse Duration (s)

Fig. 5 Normalized Transient Response

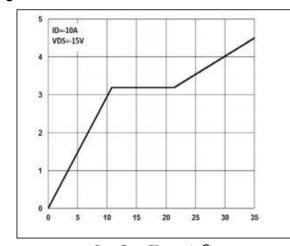
Normalized On Resistance (m^{Ω})



TJ, Juction Temperature(°C)

Fig. 2 Normalized RDSON vs. TJ

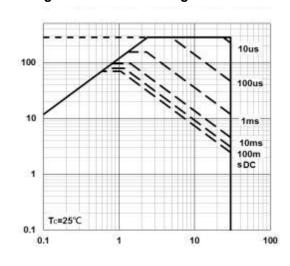
-VGS, Gate to Source Voltage (V)



Qg, Gate Charge (nC)

Fig. 4 Gate Charge Waveform

-ID, Continuous Drain Current (A)

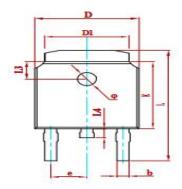


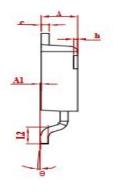
V_{DS} , Drain to Source Voltage(v)

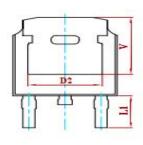
Fig. 6 Maximum Safe Operation Area



PACKAGE MECHANICAL DATA

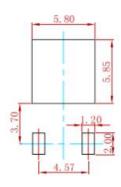






Symbol	Dimensions	In Millimeters	Dimensions	In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063 REF.	
L4	0.600	1.000	0.024	0.039
Ф	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5 250) RFF	0.207	RFF

Suggested Pad Layout



Note:

- 1.Controlling dimension in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AOD403	TO-252	2500



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